

FNK N-Channel Enhancement Mode Power MOSFET

Description

The FNK03N02D uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications.

General Features

V_{DS} =30V,I_D =140A

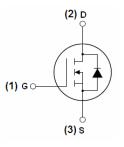
 $R_{DS(ON)}$ <3.5 m Ω @ V_{GS} =10V

 $R_{DS(ON)}$ <4.0m Ω @ V_{GS} =4.5V

- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E_{AS}
- Excellent package for good heat dissipation
 Special process technology for high ESD capability

Application

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply



Schematic diagram



Marking and pin Assignment



To-263 Top View

Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
FNK03N02D	FNK03N02D	TO-263-2L	-	-	-

Absolute Maximum Ratings (T_C=25 ℃ unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V _{DS}	30	V
Gate-Source Voltage	V _{GS}	±20	V
Drain Current-Continuous	I _D	140	Α
Drain Current-Continuous(T _C =100 °C)	I _D (100℃)	105	А
Pulsed Drain Current	I _{DM}	560	А
Maximum Power Dissipation	P _D	130	W
Derating factor		0.87	W/°C
Single pulse avalanche energy (Note 5)	E _{AS}	850	mJ
Operating Junction and Storage Temperature Range	T_{J}, T_{STG}	-55 To 175	$^{\circ}$ C

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Thermal Characteristic

Thermal Resistance,Junction-to-Case ^(Note 2)	$R_{ heta JC}$	1.15	°C/W	
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Electrical Characteristics (T_C=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit	
Off Characteristics				•			
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =250μA 30		34	-	V	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =30V,V _{GS} =0V	-	-	1	μΑ	
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V,V _{DS} =0V	-	-	±100	nA	
On Characteristics (Note 3)	-			ı			
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS},I_{D}=250\mu A$	1.0	1.2	2.0	V	
Dunin Course On Otata Basistana	_	V _{GS} =10V, I _D =20A	-	2.2	3.4	mΩ	
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =4.5V, I _D =10A		2.6	4.0		
Forward Transconductance	g FS	V _{DS} =10V,I _D =20A	32	-	-	S	
Dynamic Characteristics (Note4)	<u> </u>		•	•		•	
Input Capacitance	C _{lss}	\/ 45\/\/ O\/	-	5400	-	PF	
Output Capacitance	Coss	V_{DS} =15V, V_{GS} =0V,	-	720	-	PF	
Reverse Transfer Capacitance	C_{rss}	F=1.0MHz	-	560	-	PF	
Switching Characteristics (Note 4)	<u> </u>		•	•		•	
Turn-on Delay Time	$t_{d(on)}$		-	26	-	nS	
Turn-on Rise Time	t _r	V_{DD} =15 V , I_D =2 A , R_L =15 Ω	-	24	-	nS	
Turn-Off Delay Time	$t_{d(off)}$	V_{GS} =10V, R_{G} =2.5 Ω	-	91	-	nS	
Turn-Off Fall Time	t _f		-	39	-	nS	
Total Gate Charge	Qg	\/ 45\/ L 004	-	38		nC	
Gate-Source Charge	Q_{gs}	$V_{DS}=15V,I_{D}=30A,$ $V_{GS}=10V$	-	9		nC	
Gate-Drain Charge	Q_{gd}	V _{GS} =10V	-	13		nC	
Drain-Source Diode Characteristics	<u> </u>		•	•		•	
Diode Forward Voltage (Note 3)	V_{SD}	V _{GS} =0V,I _S =150A	-		1.2	V	
Diode Forward Current (Note 2)	Is		-	-	150	Α	
Reverse Recovery Time	t _{rr}	TJ = 25°C, IF = 20A	-	42	-	nS	
Reverse Recovery Charge	Qrr	$di/dt = 100A/\mu s^{(Note3)}$	-	39	-	nC	
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LE				y LS+LD)	

Notes:

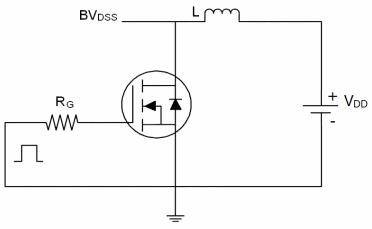
- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2. Surface Mounted on FR4 Board, t ≤ 10 sec.
- **3.** Pulse Test: Pulse Width \leq 300µs, Duty Cycle \leq 2%.
- 4. Guaranteed by design, not subject to production
- **5.** E_{AS} condition : Tj=25 $^{\circ}$ C,V_{DD}=20V,V_G=10V,L=0.5mH,Rg=25 Ω , I_{AS}=58.5A

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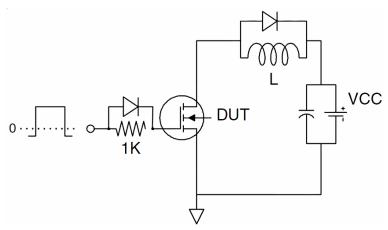


Test circuit

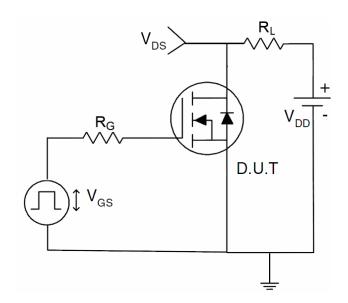
1) E_{AS} Test Circuit



2) Gate Charge Test Circuit



3) Switch Time Test Circuit



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Typical Electrical and Thermal Characteristics (Curves)

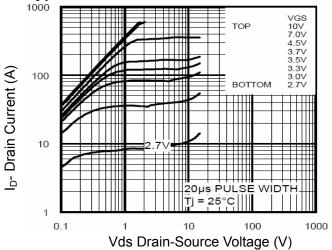


Figure 1 Output Characteristics

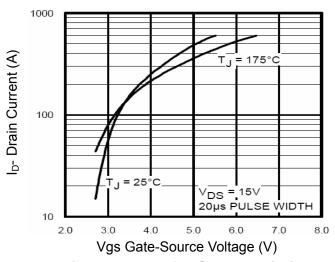


Figure 2 Transfer Characteristics

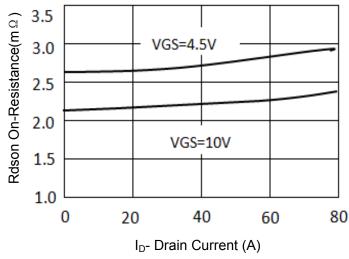


Figure 3 Rdson- Drain Current

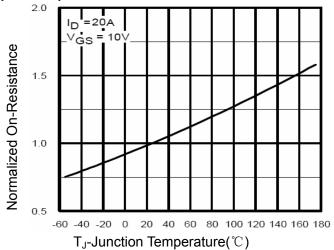


Figure 4 Rdson-JunctionTemperature

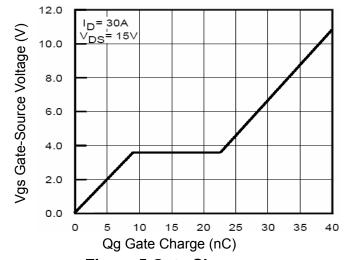


Figure 5 Gate Charge

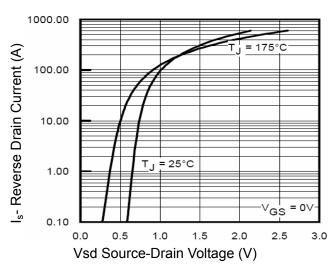


Figure 6 Source- Drain Diode Forward

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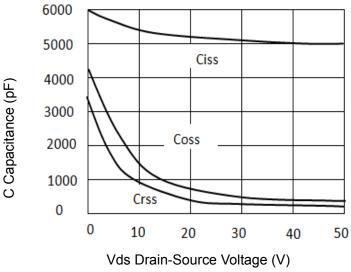


Figure 7 Capacitance vs Vds

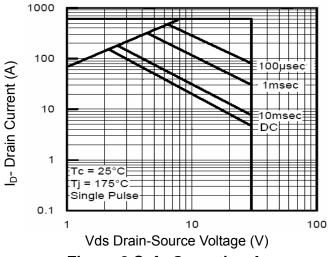


Figure 8 Safe Operation Area

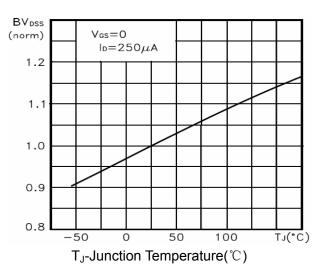


Figure 9 BV_{DSS} vs Junction Temperature

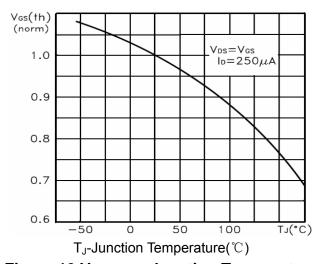


Figure 10 V_{GS(th)} vs Junction Temperature

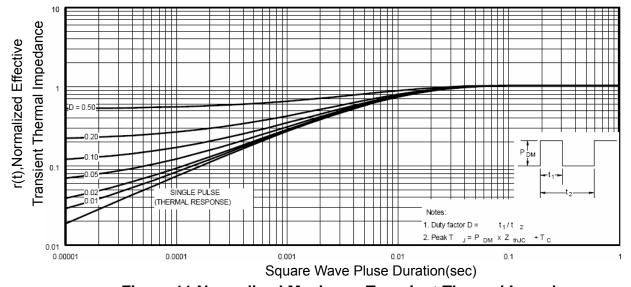
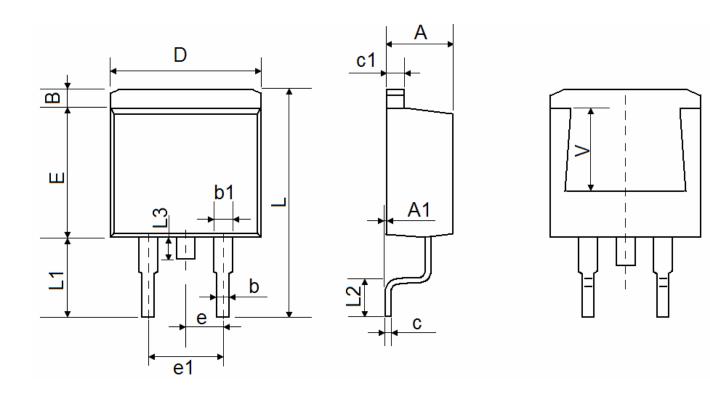


Figure 11 Normalized Maximum Transient Thermal Impedance

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TO-263 Package Information



Comment	Dimensions	In Millimeters	Dimensions In Inches		
Symbol	Min.	Max.	Min.	Max.	
А	4.470	4.670	0.176	0.184	
A1	0.000	0.150	0.000	0.006	
В	1.170	1.370	0.046	0.054	
b	0.710	0.910	0.028	0.036	
b1	1.170	1.370	0.046	0.054	
С	0.310	0.530	0.012	0.021	
c1	1.170	1.370	0.046	0.054	
D	10.010	10.310	0.394	0.406	
Е	8.500	8.900	0.335	0.350	
е	2.540	2.540 TYP.		TYP.	
e1	4.980	5.180	0.196	0.204	
L	15.050	15.450	0.593	0.608	
L1	5.080	5.480	0.200	0.216	
L2	2.340	2.740	0.092	0.108	
L3	1.300	1.700	0.051	0.067	
V	5.600 REF		0.220	REF	



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